

INFORMATION DISCLOSED CITATION <i>(Use several sheets if necessary)</i>			Docket Number (Optional)	Application Number
			Applicant(s) Larry Hryshko	81190-2502 MRW 10/530868
			Filing Date	Group Art Unit

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

## U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		2002/064841	May 30/02	Mark A Reed et al.			

## FOREIGN PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO
	02/29402	Apr. 11/02	WO				
	01/94939	Dec. 13/01	WO				
	01/48475	July 5/01	WO				
	02/64253	Aug 22/02	WO				

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

Mosbacher J et al, "Studying Membranes With Scanning Force Microscopy and Patch-Clamp Technique", Journal of Vacuum Science and Technology: Part B, American Institute of Physics, vol. 14, no. 2, March 1, 1996, pages 1449-1452.
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EXAMINER	DATE CONSIDERED
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